

Abstract Submitted  
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**Transport Properties of CVD Grown TMDs on Flat and Patterned Substrates** JOSEPH MARTINEZ, ARIANA NGUYEN, University of California Riverside, THOMAS SCOTT, University of Nebraska-Lincoln, EDWIN PRECIADO, VELVETH KLEE, University of California Riverside, DEZHENG SUN, Columbia University, PANKAJ SHARMA, University of Nebraska-Lincoln, I-HSI LU, DAVID BARROSO, University of California Riverside, SUKHYUN KIM, Columbia University, V. YA. SHUR, Ural Federal University, ALEXEI GRUVERMAN, PETER A. DOWBEN, University of Nebraska-Lincoln, LUDWIG BARTELS, University of California Riverside — Transition Metal Dichalcogenides (TMDs),  $\text{MX}_2$  ( $\text{M}=\text{Mo}, \text{W}, \text{etc.}, \text{X}=\text{S}, \text{Se}, \text{Te}$ ), have shown great promise for applications as electronic, spintronic and photonic materials. We show growth of  $\text{MX}_2$  materials under UHV (ultrahigh vacuum) and via CVD (chemical vapor deposition) on both flat and patterned substrates. Deposition on periodically-poled ferroelectric substrates reveals the impact of poling domains and the ability to reversibly invert the transport characteristics from n- to p-doped. 3D geometric patterning of substrates permits the growth across trenches and at angles to the substrate plane leading to modifications of the commonly-addressed in-plane transport properties.

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